

In the Specification:

Please amend paragraph [0001] on page 1 as follows:

--This application claims the benefit under 35 U.S.C. § 120 to PCT application PCT/DE02/03830, filed on October 11, 2002, entitled "Probe Needle for Testing Semiconductor Chips and Method for Producing Said Probe Needle" and was not published in English ~~on May 1, 2003 as International Publication No. WO 03/035541 A2~~, and which is based on German Application No. 101 50 291.5, filed October 15, 2001, both of which applications are hereby incorporated herein by reference.